Appln. No. 10/747,741

Reply to Office Action of November 9, 2009

Amendment dated: May 10, 2010

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the

application:

Claims 1 - 15. (Canceled)

16. (Currently Amended) A solid state imaging element, comprising:

a plurality of pixels arranged in a matrix, each of which has a photoelectric

conversion element, a transfer switch for transferring charge stored in said photoelectric

conversion element, a charge store part for storing charge transferred by said transfer

switch, a reset switch for resetting said charge store part, and

an amplifying element for outputting a signal in accordance with a potential of

said charge stored in said charge store part;

wherein a threshold voltage of said amplifying element is reduced in relation to

remaining transistors of each pixel, and further wherein a diffusion region that is

connected to a power source is laid out to be physically adjacent to the photoelectric

conversion element in order to provide an overflow path.

17. (Previously Presented) A solid-state imaging element according to claim 16,

wherein said transfer switch is an enhancement type transistor.

18. (Previously Presented) A solid state imaging element according to claim 16,

wherein said amplifying element is an enhancement type transistor.

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19. (Currently Amended) A solid state imaging element comprising:

a pixel, which has a photoelectric transfer element, a transfer switch for transferring charge stored in said photoelectric transfer element, a charge store part for storing charge transferred by said transfer switch, a reset switch for resetting said charge store part, and an amplifying element for outputting a signal in accordance with a potential of said charge stored in said charge store part;

wherein negative voltage is applied to a gate of said reset switch, and further wherein a threshold voltage of said amplifying element is reduced in relation to remaining transistors of each pixel, and wherein a diffusion region that is connected to a power source is laid out to be physically adjacent to the photoelectric conversion element in order to provide an overflow path.

- 20. (Previously Presented) The solid state imaging element of claim 16, wherein the amplifying element operates linearly across its entire range of operation.
- 21. (Previously Presented) The solid state imaging element of claim 17, wherein the amplifying element operates linearly across its entire range of operation.
- 22. (Previously Presented) The solid state imaging element of claim 18, wherein the amplifying element operates linearly across its entire range of operation.
- 23. (Previously Presented) The solid state imaging element of claim 19, wherein the amplifying element operates linearly across its entire range of operation.

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